

REVISIONS			
LTR	DESCRIPTION	DATE (YR-MO-DA)	APPROVED
A	Make changes to paragraphs 1.3, 4.3.1c, table I, and figure 3. Make editorial changes throughout.	89-01-30	M. A. FRYE
B	Add one vendor, CAGE 07933. Make changes to table I and editorial changes throughout. Remove vendor CAGE 34371. Device 013X is not available from an approved source of supply.	90-05-30	M. A. FRYE
C	Changes in accordance with N.O.R. 5962-R013-91.	91-09-27	M. A. FRYE
D	Drawing updated to reflect current requirements. - ro	02-07-08	R. MONNIN

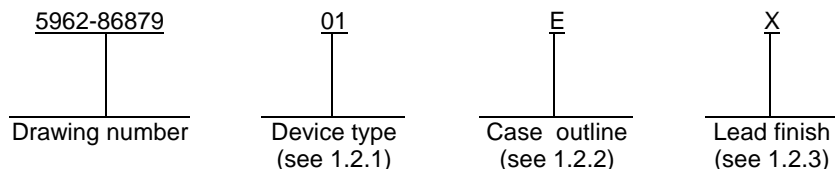
THE ORIGINAL FIRST SHEET OF THIS DRAWING HAS BEEN REPLACED.

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REV STATUS	REV	D	D	D	D	D	D	D	D	D	D	D	D	D	D					
OF SHEETS	SHEET	1	2	3	4	5	6	7	8	9	10	11	12							
PMIC N/A	PREPARED BY DONALD R. OSBORNE		<p align="center">DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216 http://www.dscc.dla.mil</p>																	
<p align="center">STANDARD MICROCIRCUIT DRAWING</p> <p>THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE</p> <p align="center">AMSC N/A</p>	CHECKED BY RAY MONNIN																			
	APPROVED BY MICHAEL A. FRYE																			
	DRAWING APPROVAL DATE 88-05-05																			
	REVISION LEVEL D																			
		SIZE A	CAGE CODE 67268	5962-86879																
		SHEET 1 OF 12																		

1. SCOPE

1.1 Scope. This drawing describes device requirements for MIL-STD-883 compliant, non-JAN class level B microcircuits in accordance with MIL-PRF-38535, appendix A.

1.2 Part or Identifying Number (PIN). The complete PIN is as shown in the following example:



1.2.1 Device type(s). The device type(s) identify the circuit function as follows:

<u>Device type</u>	<u>Generic number</u>	<u>Circuit function</u>
01	HS-3182, HI-8382	Bus interface line driver circuit

1.2.2 Case outline(s). The case outline(s) are as designated in MIL-STD-1835 and as follows:

<u>Outline letter</u>	<u>Descriptive designator</u>	<u>Terminals</u>	<u>Package style</u>
E	GDIP1-T16 or CDIP2-T16	16	Dual-in-line
3	CQCC1-N28	28	Square leadless chip carrier

1.2.3 Lead finish. The lead finish is as specified in MIL-PRF-38535, appendix A.

1.3 Absolute maximum ratings.

V+ minus V- (differential voltage)	40 V dc
V ₁	7 V dc
V _{REF}	6 V dc
Logic input voltage range	(GND - 0.3 V) to (V ₁ + 0.3 V)
Maximum power dissipation (P _D):	
Case E	1.725 W <u>1/</u>
Case 3	1.12 W <u>1/</u>
Junction temperature (T _J)	+175°C
Lead temperature (soldering, 10 seconds)	+275°C
Storage temperature range	-65°C to +150°C
Thermal resistance, junction-to-case (θ _{JC})	See MIL-STD-1835
Thermal resistance, junction-to-ambient (θ _{JA}):	
Case E	86.5°C/W
Case 3	133.7°C/W

1/ Derate above +25°C, 11.5 mW/°C for case E, and 7.5 mW/°C for case 3.

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1.4 Recommended operating conditions. 2/

Supply voltage:

V+	15 V dc ±10%
V-	-15 V dc ±10%
V ₁	5 V dc ±5%
V _{REF}	5 V dc ±5%

Ambient operating temperature range (T_A) -55°C to +125°C

Maximum load:

Data rate at 12.5 KBPS: R_L = 800 Ω, C_L = 30 nF; R_L = 400 Ω, C_L = 6.9 nF.

Data rate at 100 KBPS: R_L = 800 Ω, C_L = 4 nF.

2. APPLICABLE DOCUMENTS

2.1 Government specification, standards, and handbooks. The following specification, standards, and handbooks form a part of this drawing to the extent specified herein. Unless otherwise specified, the issues of these documents are those listed in the issue of the Department of Defense Index of Specifications and Standards (DoDISS) and supplement thereto, cited in the solicitation.

SPECIFICATION

DEPARTMENT OF DEFENSE

MIL-PRF-38535 -- Integrated Circuits, Manufacturing, General Specification for.

STANDARDS

DEPARTMENT OF DEFENSE

- MIL-STD-883 - Test Method Standard Microcircuits.
- MIL-STD-1835 - Interface Standard Electronic Component Case Outlines.

HANDBOOKS

DEPARTMENT OF DEFENSE

- MIL-HDBK-103 -- List of Standard Microcircuit Drawings.
- MIL-HDBK-780 - Standard Microcircuit Drawings.

(Unless otherwise indicated, copies of the specification, standards, and handbooks are available from the Standardization Document Order Desk, 700 Robbins Avenue, Building 4D, Philadelphia, PA 19111-5094.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

2/ All voltages referenced to GND

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3. REQUIREMENTS

3.1 Item requirements. The individual item requirements shall be in accordance with MIL-PRF-38535, appendix A for non-JAN class level B devices and as specified herein. Product built to this drawing that is produced by a Qualified Manufacturer Listing (QML) certified and qualified manufacturer or a manufacturer who has been granted transitional certification to MIL-PRF-38535 may be processed as QML product in accordance with the manufacturers approved program plan and qualifying activity approval in accordance with MIL-PRF-38535. This QML flow as documented in the Quality Management (QM) plan may make modifications to the requirements herein. These modifications shall not affect form, fit, or function of the device. These modifications shall not affect the PIN as described herein. A "Q" or "QML" certification mark in accordance with MIL-PRF-38535 is required to identify when the QML flow option is used.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38535, appendix A and herein.

3.2.1 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.

3.2.2 Terminal connections. The terminal connections shall be as specified on figure 1.

3.2.3 Truth table. The truth table shall be as specified on figure 2.

3.2.4 Logic diagram. The logic diagram shall be as specified on figure 3.

3.3 Electrical performance characteristics. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full ambient operating temperature range.

3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.

3.5 Marking. Marking shall be in accordance with MIL-PRF-38535, appendix A. The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked as listed in MIL-HDBK-103 (see 6.6 herein). For packages where marking of the entire SMD PIN number is not feasible due to space limitations, the manufacturer has the option of not marking the "5962-" on the device.

3.5.1 Certification/compliance mark. A compliance indicator "C" shall be marked on all non-JAN devices built in compliance to MIL-PRF-38535, appendix A. The compliance indicator "C" shall be replaced with a "Q" or "QML" certification mark in accordance with MIL-PRF-38535 to identify when the QML flow option is used.

3.6 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-HDBK-103 (see 6.6 herein). The certificate of compliance submitted to DSCC-VA prior to listing as an approved source of supply shall affirm that the manufacturer's product meets the requirements of MIL-PRF-38535, appendix A and the requirements herein.

3.7 Certificate of conformance. A certificate of conformance as required in MIL-PRF-38535, appendix A shall be provided with each lot of microcircuits delivered to this drawing.

3.8 Notification of change. Notification of change to DSCC-VA shall be required in accordance with MIL-PRF-38535, appendix A.

3.9 Verification and review. DSCC, DSCC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

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TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions -55°C ≤ T _A ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Supply current V+ (operating)	I _{CCOP} (V+)	No load (0-100 k bits/s)	1,2,3	01		16	mA
Supply current V- (operating)	I _{CCOP} (V-)	No load (0-100 k bits/s)	1,2,3	01		-16	mA
Supply current V ₁ (operating)	I _{CCOP} (V ₁)	No load (0-100 k bits/s)	1,2,3	01		975	μA
Supply current V _{REF} (operating)	I _{CCOP} (V _{REF})	No load (0-100 k bits/s)	1,2,3	01		-1.0	mA
Supply current V- (during short circuit test)	I _{SC} (V-)	Short to ground 1/	1,2,3	01		-150	mA
Supply current V+ (during short circuit test)	I _{SC} (V+)	Short to ground 1/	1,2,3	01		150	mA
Output short circuit current (output high)	I _{OSHC}	Short to ground, 2/ V _{min} = 0 V	1,2,3	01	-80		mA
Output short circuit current (output low)	I _{OSLC}	Short to ground, 2/ V _{min} = 0 V	1,2,3	01	+80		mA
Input current (input high)	I _{IH}		1,2,3	01		10	μA
Input current (input low)	I _{IL}		1,2,3	01		-20	μA
Output voltage high (output to ground)	V _{OH}	No load (0-100 k bits/s)	1,2,3	01	+V _{REF} -.25	+V _{REF} +.25	V
Output voltage low (output to ground)	V _{OL}	No load (0-100 k bits/s)	1,2,3	01	-V _{REF} -.25	-V _{REF} +.25	V
Output voltage null	V _{NULL}	No load (0-100 k bits/s)	1,2,3	01	-250	+250	mV
Input capacitance	C _{IN}	See 4.3.1c, T _A = +25°C	4	01		30	pF
Functional tests		V _{IH} = 2.0 V, 3/ V _{IL} = 0.5 V, see 4.3.1d	7,8	01			

See footnotes at end of table.

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TABLE I. Electrical performance characteristics – Continued.

Test	Symbol	Conditions -55°C ≤ T _A ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit	
					Min	Max		
Rise time (A _{OUT} , B _{OUT})	t _r	See figure 4, C _L = 75 pF	3/	9,10,11	01	0.9	2.4	μs
Fall time (A _{OUT} , B _{OUT})	t _f	See figure 4, C _L = 75 pF	3/	9,10,11	01	0.9	2.4	μs
Propagation delay input to output	t _{PLH}	See figure 4, C _L = 75 pF	3/	9,10,11	01		3.3	μs
Propagation delay input to output	t _{PHL}	See figure 4, C _L = 75 pF	3/	9,10,11	01		3.3	μs

1/ Not tested, but characterized at initial device design and after major process or design change which affects this parameter.

2/ Interchangeability of force and sense is acceptable.

3/ V₊ = 15 V, V₋ = 15 V, V₁ = V_{REF} = 5.0 V.

4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with MIL-PRF-38535, appendix A.

4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

a. Burn-in test, method 1015 of MIL-STD-883.

(1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1015 of MIL-STD-883.

(2) T_A = +125°C, minimum.

b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

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Device type	01	
Case outlines	E	3
Terminal number	Terminal symbol	
1	V _{REF}	V _{REF}
2	GND	NC
3	SYNC	GND
4	DATA (A)	SYNC
5	C _A	NC
6	A _{OUT}	DATA (A)
7	-V	NC
8	GND	NC
9	+V	C _A
10	NC	NC
11	B _{OUT}	NC
12	C _B	NC
13	DATA (B)	A _{OUT}
14	CLOCK	-V
15	NC	GND
16	V ₁	+V
17	---	B _{OUT}
18	---	NC
19	---	NC
20	---	NC
21	---	NC
22	---	C _B
23	---	DATA (B)
24	---	NC
25	---	CLOCK
26	---	NC
27	---	NC
28	---	V ₁

NC = No connection

FIGURE 1. Terminal connections.

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SYNC	CLOCK	DATA (A)	DATA (B)	AOUT	BOUT	COMMENTS
X	L	X	X	0 V	0 V	NULL
L	X	X	X	0 V	0 V	NULL
H	H	L	L	0 V	0 V	NULL
H	H	L	H	-VREF	+VREF	LOW
H	H	H	L	+VREF	-VREF	HIGH
H	H	H	H	0 V	0 V	NULL

FIGURE 2. Truth table.

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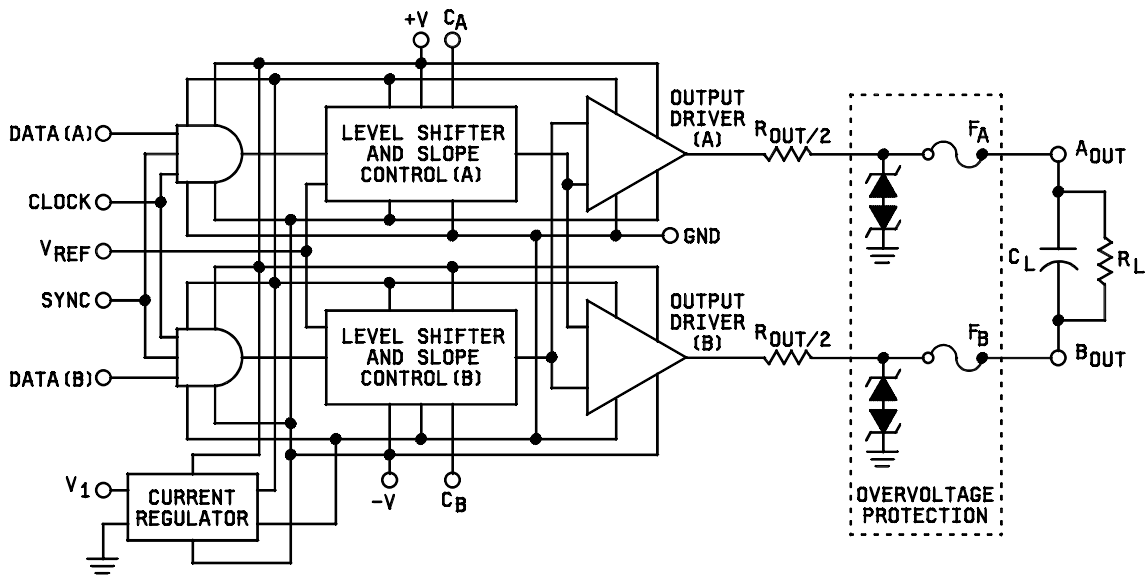


FIGURE 3. Logic diagram.

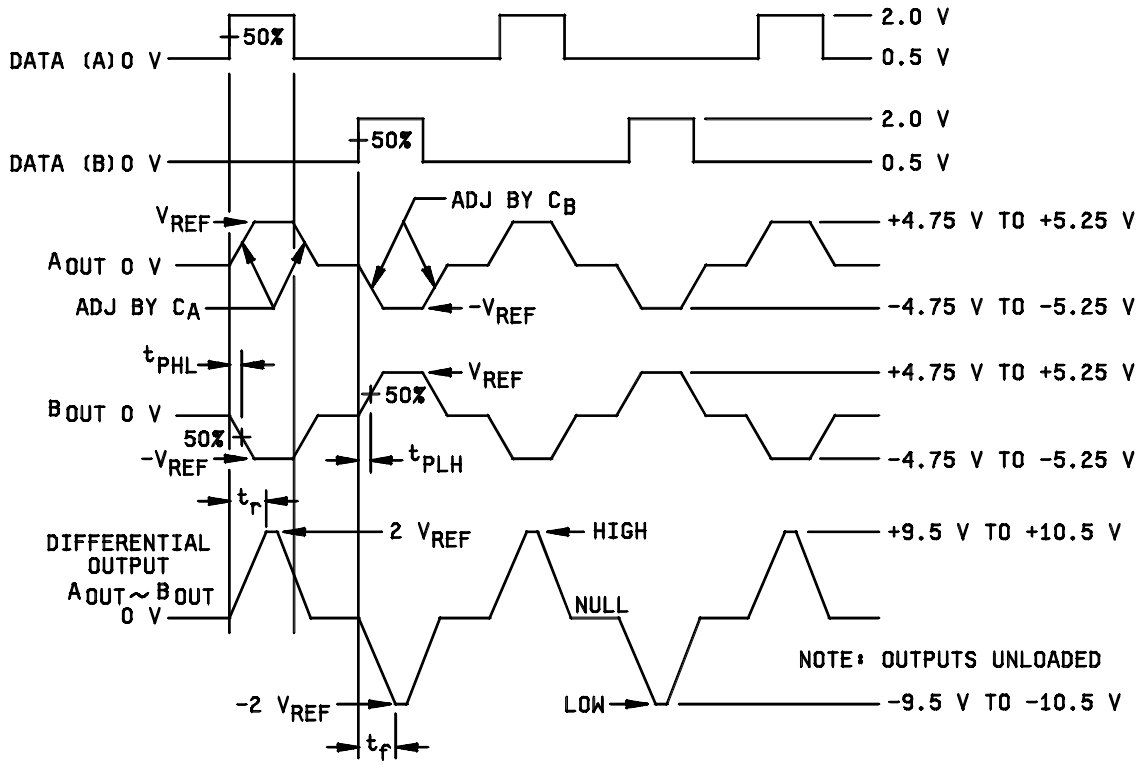
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COLUMBUS, OHIO 43216-5000

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NOTE: t_r measured 50 percent to 90 percent times two.
 t_f measured 50 percent to 90 percent times two.
 $V_{IH} = 2.0 V$ $V_{OL} = -4.75 V$ to $-5.25 V$
 $V_{IL} = 0.5 V$ $V_{OH} = 4.75 V$ to $5.25 V$

FIGURE 4. Switching waveforms.

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TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (in accordance with MIL-STD-883, method 5005, table I)
Interim electrical parameters (method 5004)	---
Final electrical test parameters (method 5004)	1*,2,3,7,8,9
Group A test requirements (method 5005)	1,2,3,4,7,8,9,10,11
Groups C and D end-point electrical parameters (method 5005)	1,2,3

* PDA applies to subgroup 1.

4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

4.3.1 Group A inspection.

- a. Tests shall be as specified in table II herein.
- b. Subgroups 5 and 6 in table I, method 5005 of MIL-STD-883 shall be omitted.
- c. Subgroup 4 (C_{IN} measurement) shall be measured only for the initial test and after process or design changes which may affect input capacitance. Sample size is 15 devices, all input and output terminals tested, and no failures.
- d. Subgroups 7 and 8 shall include verification of the truth table.

4.3.2 Groups C and D inspections.

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life test conditions, method 1005 of MIL-STD-883.
 - (1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1005 of MIL-STD-883.
 - (2) $T_A = +125^\circ\text{C}$, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-PRF-38535, appendix A.

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6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.

6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished using DD Form 1692, Engineering Change Proposal.

6.4 Record of users. Military and industrial users shall inform Defense Supply Center Columbus when a system application requires configuration control and the applicable SMD. DSCC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronics devices (FSC 5962) should contact DSCC-VA, telephone (614) 692-0544.

6.5 Comments. Comments on this drawing should be directed to DSCC-VA, Columbus, Ohio 43216-5000, or telephone (614) 692-0547.

6.6 Approved sources of supply. Approved sources of supply are listed in MIL-HDBK-103. The vendors listed in MIL-HDBK-103 have agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DSCC-VA.

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STANDARD MICROCIRCUIT DRAWING BULLETIN

DATE: 02-07-08

Approved sources of supply for SMD 5962-86879 are listed below for immediate acquisition information only and shall be added to MIL-HDBK-103 and QML-38535 during the next revision. MIL-HDBK-103 and QML-38535 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DSCC-VA. This bulletin is superseded by the next dated revision of MIL-HDBK-103 and QML-38535.

Standard microcircuit drawing PIN <u>1/</u>	Vendor CAGE number	Vendor similar PIN <u>2/</u>
5962-8687901EA	34371	HS1-3182/883
	44270	HI-8382CM-03
	<u>3/</u>	HI-8382CM-02
	<u>3/</u>	RM3182S/883B
5962-86879013A	<u>3/</u>	HI-8382SM-02
	<u>3/</u>	HS4-3182/883

- 1/ The lead finish shown for each PIN representing a hermetic package is the most readily available from the manufacturer listed for that part. If the desired lead finish is not listed contact the vendor to determine its availability.
- 2/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.
- 3/ Not available from an approved source of supply.

Vendor CAGE
number

Vendor name
and address

34371

Intersil Corporation
P.O. Box 883
Melbourne, FL 32902-0883

44270

Holt Integrated Circuits, Inc.
23351 Madero
Mission Viejo, CA 92691-2730

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